

Probing the Nanoscale

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With the rapid and exciting progress in producing new and advanced nanomaterials that increasingly find applications in consumer products, capabilities for probing and analyzing these materials have lagged behind. During this lecture we will discuss the tools that are used to investigate, manipulate and control objects and phenomena at the nanoscale. In particular, we will discuss the principles and applications of Atomic Force Microscopy (AFM), Scanning Tunneling Microscopy (STM) as well as optical, x-ray and electron microscopy.